Ga₂O₃ for power electronics and its thermal properties

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β -Ga₂O₃ is the stable phase of the Ga₂O₃ crystalline system, which is widely researched now.



Fig. 1 Transformation relationships among the crystalline phases of Ga2O3 and their hydrates [30]

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Introduction of β -Ga₂O₃





Unit cell and properties of β-Ga₂O₃

- Crystal structure: Monoclinic
- Energy band-gap: 4.8 eV
- Bulk substrate: Melt-growth method
- n-type doping: Shallow donors

(Si, Ge, Sn...)



Parameters of major semiconductors

attico	constant.	
Lattice	constant.	

а	=	1.22	nm
b	=	0.30	nm
C	=	0.58	nm
α	=	90°	
αβ	=	90° 104°	

	Si	4H-SiC	GaN	Diamond	β -Ga ₂ O ₃
Band gap (eV)	1.1	3.3	3.4	5.5	4.8
Electron mobility (cm ² V ⁻¹ s ⁻¹)	1,500	1,000	1,200	1,800	300 ^{a)}
Breakdown field (MV/cm)	0.3	3.0	3.3	10	8 ^{a)}
Dielectric constant	11.8	10	9.5	5.5	10
Baliga's FOM (low freq.)	1	570	860	21,000	3,200
a) Estimated					

K. Sasaki et al., 2012 Appl. Phys. Express 5 035502 (2012).





The growth of Ga_2O_3 has been promoted by the realization of high-quality bulk substrates.



- High quality single crystal substrate was available since 2008.
- First MOSFET demonstration in 2012.
- Mist CVD-grown Ga₂O₃ based diodes have reached mass-production phase.



D. Shinohara et al., Jpn. J. Appl. Phys. 47, 7311 (2008). https://flosfia.com/products/

Highly-cited research

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Power electronics are applied to all over the electric ecosystem. Schottky barrier diode is one kind of power devices among thyristors, bipolar transistors and MOSFETs.



J. Zhang *et al.*, APL Mater. **8**, 020906 (2020).

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E. Farzana et al., Appl. Phys. Lett. 118, 162109 (2021).

GaN power electronics in an EV

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The GaN revolution: Transphorm talks – Products to applications fueling the new power semiconductor market www.i-micronews.com



Power electronics in EVs



Nissan Leaf S,S Plus

Lithium-ion battery

Si-based power electronics



Battery size: 40 kWh, 62 kWh

Tesla Model 3 Standard range, Long range

Lithium-ion battery

SiC-based power electronics



60 kWh, 82 kWh

 Range: 149 miles, 226 miles
 272 miles, 358 miles

 21.2%
 more efficient

 kWh per mile: 0.268, 0.274
 0.221, 0.229

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Specs for different inverters





Side-by-Side Comparison

100	MUNRO
-	& ASSOCIATES, INC.

Battery Elect	ric Vehicles	(BEV)	 Inverter
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	2018 Tesla Model 3 Inverter	2019 Nissan Leaf Inverter	2019 Jaguar I-Pace Inverter
	and the second s		A REAL PROPERTY OF THE PARTY OF
Cost (USD)	\$522.22	\$468.41	\$555.29
Max. Input Voltage (V _{DC})	430	450	500
Dimensions (mm)	370 x 278 x 122	386 x 386 x 223	407 x 272 x 83
Parts / Fasteners	1275 / 44	1287 / 56	2185 / 106
Weight (kg)	4.81	11.15	8.23
Coolant Medium	Water/Glycol	Water/Glycol	Water/Glycol

Cost and weights include: Housing, PCBA, IGBT Module & Cooling Structure, DC-link Capacitor, Motor Phase Lead, Connectors, Self-contained structural and connected components.

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From another point of view, gallium oxide shows poor thermal conductivity compared to major semiconductor materials.

Semiconductor material	Si	GaN	4H-SiC	β -Ga ₂ O ₃
Bandgap E _g (eV)	1.1	3.4	3.3	4.7–4.9
Electron mobility μ (cm ² V ⁻¹ s ⁻¹)	1400	1200	1000	300
Breakdown electric field E _{br} (MV/cm)	0.3	3.3	2.5	8
Baliga's FOM (εμE ³)	1	870	340	3444
Thermal conductivity λ (W cm ⁻¹ K ⁻¹)	1.5	2.1	2.7	0.11

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Debye model study





Guo et al., Appl. Phys. Lett. 106, 111909 (2015).

SPECK GROUP Nitride and Oxide Thin Film Epitoxy and Characterization **T-dependent thermal conductivity**





Table 1 Thermal conductivity of the bulk β -Ga₂O₃ at 300 K

Z. Yan and S. Kumar, Phys. Chem. Chem. Phys. 20, 29236 (2018).





 β -Ga₂O₃ has a much shorter phonon lifetime than GaN in the entire frequency domain.

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Z. Yan and S. Kumar, Phys. Chem. Chem. Phys. 20, 29236 (2018).

SPECK GROUP Phonon dispersion of β-Ga₂O₃

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Large gap between acoustic phonon and optical phonon in β -Ga₂O₃ system.



Z. Yan and S. Kumar, Phys. Chem. Chem. Phys. 20, 29236 (2018).



Schematic layout of the investigated β -Ga₂O₃ single finger metal–semiconductor field-effect transistor (MESFET)

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C. Yuan, Y. Zhang, R. Montgomery, S. Kim, Ji. Shi, A. Mauze, **T. Itoh**, J. S Speck, S. Graham, J. App. Phys. **127**, 54502 (2020).

SPECK GROUP Device structures for simulations





TABLE II. Va	riable's range,	baseline,	and c	ptimal	cooling	values
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Variables	Range	Baseline	Optimal cooling parameter
Ga_2O_3 thickness (t_g) (μ m)	1-100	10	1
Thermal boundary conductance (TBC) $(MW/m^2 K)$	5-200	20	200
Substrate thermal conductivity (k_s) (W/m K)	35-2000	400	2000
Underfill thermal conductivity (k_f) (W/m K)	0.2-11	2	11
Bump joint thermal conductivity (k_b) (W/m K)	10-200	50	200
Heat spreader deposited at the active region (W/m K)	10-500	300	500

C. Yuan, Y. Zhang, R. Montgomery, S. Kim, Ji. Shi, A. Mauze, **T. Itoh**, J. S Speck, S. Graham, J. App. Phys. **127**, 54502 (2020).

Results of Simulation



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Thank you!